


<b>Search Notes</b>  	<b>Application/Control No.</b>  10584334	<b>Applicant(s)/Patent Under Reexamination</b>  SHIN ET AL.
	<b>Examiner</b>  JULIO PEREZ	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	423, 37.11	5/7/2010	JP
Updated search		11/27/2010	JP
455	446, 453	11/27/2010	JP
455	423, 67.1, 67.2, 67.4	5/31/2011	JP

SEARCH NOTES		
Search Notes	Date	Examiner
East (text search)	5/7/2010	JP
Inventor's search	5/7/2010	JP
Inventor's search	11/27/2010	JP
Consulted Wayne Cai	5/31/2011	JP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/J. P./ Examiner.Art Unit 2617	
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